

STS25NH3LL

N-channel 30 V - 0.0032 Ω - 25 A - SO-8 STripFET™ III Power MOSFET for DC/DC conversion

Features

Туре	V _{DSS}	R _{DS(on)}	I _D
STS25NH3LL	30 V	<0.0035 Ω	25 A ⁽¹⁾

- 1. This value is rated according to Rthj-pcb
- Optimal R_{DS(on)} x Qg trade off @ 4.5 V
- Conduction losses reduced
- Switching losses reduced

Applications

Switching applications

Description

ns

This device utilizes the advanced design rules of ST's proprietary STripFET[™] technology. The innovative process coupled with unique metallization techniques makes it possible to produce the most advanced low voltage Power MOSFET in an SO-8 package. The device is therefore suitable for demanding DC-DC converter applications where high efficiency at high output current is needed.

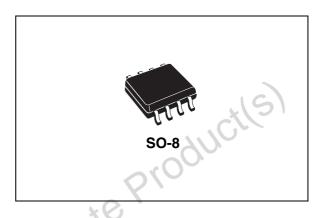


Figure 1. Internal schematic diagram

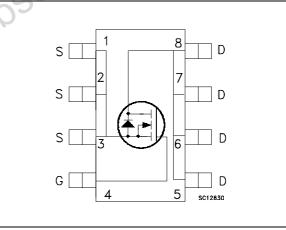


Table 1. Device summary	nmary	sum	Device	e 1.	Table
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Order code	Marking	Package	Packaging
STS25NH3LL	25H3LL	SO-8	Tape & reel

Electrical ratings 1

Table 2.	Absolute	maximum	ratings
	Absolute	maximum	raungs

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage ($V_{GS} = 0$)	30	V
V _{GS}	Gate-source voltage	± 18	V
I _D ⁽¹⁾	Drain current (continuous) at $T_C = 25 \ ^{\circ}C$	25	А
Ι _D	Drain current (continuous) at T _C =100 °C	18	А
I _{DM} ⁽²⁾	Drain current (pulsed)	100	А
P _{TOT} ⁽¹⁾	Total dissipation at $T_C = 25 \ ^{\circ}C$	3.2	W
	e is rated according to Rthj-pcb th limited by safe operating area	9/10-	
Table 3.	Thermal data	Proc	
Symbol	Parameter	Value	Unit

Table 3. Thermal data

Symbol	Parameter	Value	Unit
R _{thj-pcb} ⁽¹⁾	Thermal resistance junction-amb max	47	°C/W
1	Operation junction temperature Storage temperature	-55 to 175	°C

1. When mounted on FR-4 board of 1 inch², 2 oz Cu, t< 10 sec

Table 4. Avalanche characteristics

	Symbol	Parameter	Value	Unit
	I _{AV}	Not-repetitive avalanche current (pulse width limited by Tj max.)	12.5	А
10	E _{AS}	Single pulse avalanche energy (starting Tj = 25 °C, $I_D = I_{AV}$, $V_{DD} = 24$ V)	1.3	J
0050.				

Electrical characteristics 2

(T_{CASE}=25°C unless otherwise specified)

V(BR)DSSDrain-source breakdown voltageID $250 \ \mu$ A, VGS = 030IDIDSSDrain-source breakdown voltageID $= 250 \ \mu$ A, VGS = 030IDIDIDSSZero gate voltage drain current (VGS = 0)VDS = Max rating, VDS = Max rating @ 125 °CIDIDIDIGSSGate body leakage current (VDS = 0)VGS = $\pm 18 \ V$ ID $\pm 100 \ \pm 100 \ ID$ IDVGS(th)Gate threshold voltageVDS = VGS, ID = 250 \ \muAIDIDIDRDS(on)Static drain-source on resistanceVGS = $10 \ V, ID = 12.5 \ A \ VGS = 4.5 \ VGS $		on, on otatoo					
$V_{(BR)DSS}$ voltage $I_D = 250 \ \mu A, \ V_{GS} = 0$ 30 1 I_{DSS} Zero gate voltage drain current ($V_{GS} = 0$) $V_{DS} = Max \ rating,$ $V_{DS} = Max \ rating @ 125 °C$ 1 1 I_{GSS} Gate body leakage current ($V_{DS} = 0$) $V_{GS} = \pm 18 \ V$ 1 ± 100 $V_{GS(th)}$ Gate threshold voltage $V_{DS} = V_{GS}, \ I_D = 250 \ \mu A$ 1 $ R_{DS(on)}$ Static drain-source on resistance $V_{GS} = 10 \ V, \ I_D = 12.5 \ A$ $0.0032 \ 0.0035 \ 0.004$ 0.005	Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
IDSSCurrent (V_{GS} = 0)VDS = Max rating @ 125 °C10IGSSGate body leakage current (VDS = 0) $V_{GS} = \pm 18 V$ ± 100 VGS(th)Gate threshold voltage $V_{DS} = V_{GS}, I_D = 250 \mu A$ 1RDS(on)Static drain-source on resistance $V_{GS} = 4.5 V, I_D = 12.5 A$ 0.0032 0.0040.0035 0.005	V _{(BR)DSS}		$I_{D} = 250 \ \mu A, \ V_{GS} = 0$	30			V
IGSS $(V_{DS} = 0)$ $V_{GS} = \pm 18 \text{ V}$ ± 100 VGS(th) Gate threshold voltage $V_{DS} = V_{GS}, I_D = 250 \mu A$ 1 ± 100 RDS(on) Static drain-source on resistance $V_{GS} = 10 \text{ V}, I_D = 12.5 \text{ A}$ 0.0032 0.0035 RDS(on) Static drain-source on resistance $V_{GS} = 4.5 \text{ V}, I_D = 12.5 \text{ A}$ 0.004 0.005	I _{DSS}	. .	20			1 10	μΑ μΑ
$R_{DS(on)} \begin{array}{ c c c c c c c c c c c c c c c c c c c$	I _{GSS}		V _{GS} = ± 18 V			±100	nA
$R_{DS(on)}$ resistance V_{GS} = 4.5 V, I_{D} = 12.5 A 0.004 0.005	V _{GS(th)}	Gate threshold voltage	V_{DS} = V_{GS} , I_D = 250 μ A	1	92		V
	R _{DS(on)}						Ω Ω
Table 6. Dynamic	Table 6.	Dynamic	colete				

On/off states Table 5.

Table 6. Dynamic

Parameter	Test conditions	Min.	Тур.	Max.	Unit
Forward transconductance	V _{DS} = 10 V, I _D = 12.5 A		30		S
Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} =25 V, f = 1 MHz, V _{GS} = 0		4450 655 50		pF pF pF
Total gate charge Gate-source charge Gate-drain charge	$V_{DD} = 15 \text{ V}, \text{ I}_{D} = 25 \text{ A}$ $V_{GS} = 4.5 \text{ V}$ <i>Figure 14</i>		30 12.5 10	40	nC nC nC
Output charge	V_{DD} = 24 V, V_{GS} = 0		23		nC
Gate input resistance	f = 1 MHz, gate DC bias =0 test signal level = 20 mV open drain	1	2	3	Ω
	Forward transconductance Input capacitance Output capacitance Reverse transfer capacitance Total gate charge Gate-source charge Gate-drain charge Output charge	Forward transconductance $V_{DS} = 10 \text{ V}, I_D = 12.5 \text{ A}$ Input capacitance $V_{DS} = 25 \text{ V}, f = 1 \text{ MHz},$ Output capacitance $V_{DS} = 25 \text{ V}, f = 1 \text{ MHz},$ Reverse transfer capacitance $V_{DD} = 15 \text{ V}, I_D = 25 \text{ A}$ Total gate charge $V_{DD} = 15 \text{ V}, I_D = 25 \text{ A}$ Gate-source charge Gate-drain charge $V_{GS} = 4.5 \text{ V}$ Figure 14Output chargeOutput charge $V_{DD} = 24 \text{ V}, V_{GS} = 0$ Gate input resistance $f = 1 \text{ MHz}, \text{ gate DC bias =0}$ test signal level = 20 mV	Forward transconductance $V_{DS} = 10 \text{ V}, I_D = 12.5 \text{ A}$ Input capacitance $V_{DS} = 25 \text{ V}, f = 1 \text{ MHz},$ Output capacitance $V_{DS} = 25 \text{ V}, f = 1 \text{ MHz},$ Reverse transfer capacitance $V_{DD} = 15 \text{ V}, I_D = 25 \text{ A}$ Total gate charge $V_{DD} = 15 \text{ V}, I_D = 25 \text{ A}$ Gate-source charge Gate-drain charge $V_{GS} = 4.5 \text{ V}$ Figure 14Output chargeOutput charge $V_{DD} = 24 \text{ V}, V_{GS} = 0$ Gate input resistance $f = 1 \text{ MHz}, \text{ gate DC bias =0}$ test signal level = 20 mV	Forward transconductance $V_{DS} = 10 \text{ V}, I_D = 12.5 \text{ A}$ 30Input capacitance $V_{DS} = 25 \text{ V}, f = 1 \text{ MHz},$ 4450Output capacitance $V_{DS} = 25 \text{ V}, f = 1 \text{ MHz},$ 4450Reverse transfer capacitance $V_{DS} = 25 \text{ V}, f = 1 \text{ MHz},$ 4450Total gate charge $V_{DD} = 15 \text{ V}, I_D = 25 \text{ A}$ 30Total gate charge $V_{DD} = 15 \text{ V}, I_D = 25 \text{ A}$ 30Gate-source charge $V_{GS} = 4.5 \text{ V}$ 12.5Gate-drain charge $V_{DD} = 24 \text{ V}, V_{GS} = 0$ 23Output charge $V_{DD} = 24 \text{ V}, V_{GS} = 0$ 23Gate input resistance $f = 1 \text{ MHz}, \text{ gate DC bias =0}$ test signal level = 20 mV1	Forward transconductance $V_{DS} = 10 \text{ V}, I_D = 12.5 \text{ A}$ 30Input capacitance Output capacitance $V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0$ 4450 655 50 Total gate charge Gate-source charge Gate-drain charge $V_{DD} = 15 \text{ V}, I_D = 25 \text{ A}$ $Figure 14$ 30Output charge $V_{DD} = 15 \text{ V}, I_D = 25 \text{ A}$ $V_{GS} = 4.5 \text{ V}$ $Figure 14$ 30Output charge $V_{DD} = 24 \text{ V}, V_{GS} = 0$ 23Gate input resistance $f = 1 \text{ MHz}, \text{ gate DC bias } = 0$ test signal level $= 20 \text{ mV}$ 12

1. Pulsed: pulse duration=300 µs, duty cycle 1.5%

2. $Q_{OSS} = C_{oss} * \Delta V_{in}$, $C_{oss} = C_{gd} + C_{ds}$



Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r t _{d(off)} t _f	Turn-on delay time Rise time Turn-off delay time Fall time	V_{DD} = 15 V, I_D = 12.5 A, R _G = 4.7 Ω, V _{GS} = 10 V <i>Figure 13</i>		18 50 75 8		ns ns ns ns

Table 7. Switching times

Table 8. Source drain diode

Symbol	Parameter	Test conditions	Min	Тур.	Max	Unit
I _{SD}	Source-drain current				25	A
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)			11/2	100	А
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 25 \text{ A}, V_{GS} = 0$	0	0,2	1.3	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I _{SD} = 25 A, di/dt = 100 A/μs, V _{DD} = 25 V, T _J = 150 °C <i>Figure 18</i>		32 34 2.1		ns nC A

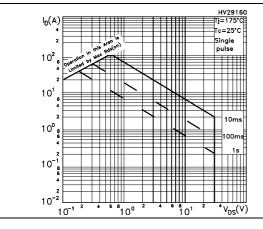
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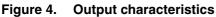
1. Pulse width limited by safe operating area

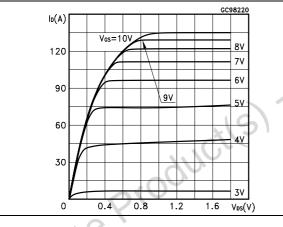
2. Pulsed: pulse duration=300 µs, duty cycle 1.5%

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area









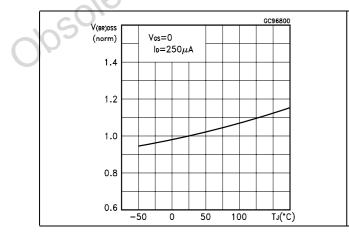
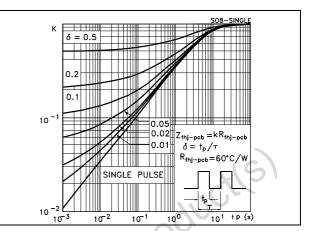


Figure 3. Thermal impedance





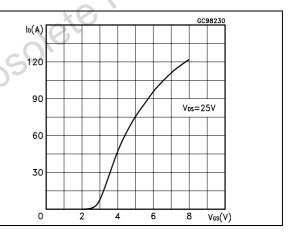
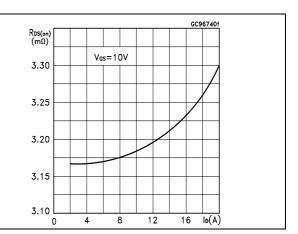


Figure 7. Static drain-source on resistance



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Gate charge vs gate-source voltage Figure 9. Capacitance variations Figure 8.

C(pF)

4800

3600

2400

1200

Crs

6

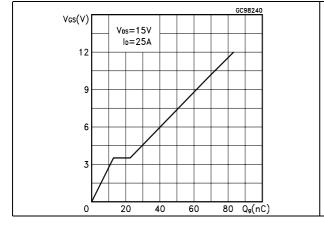
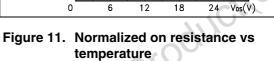


Figure 10. Normalized gate threshold voltage vs temperature



f=1MHz Vgs=0V

Cos

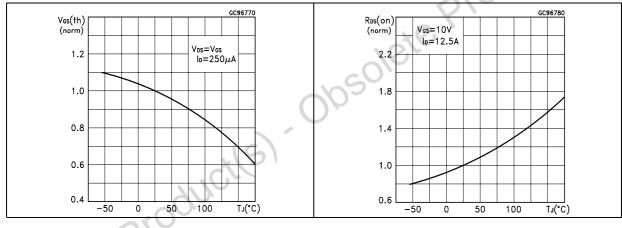
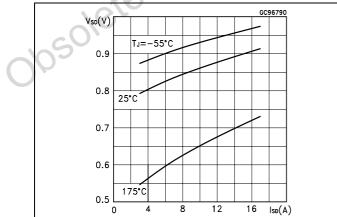


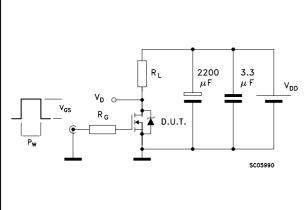
Figure 12. Source-drain diode forward characteristics





3 Test circuit

Figure 13. Switching times test circuit for resistive load



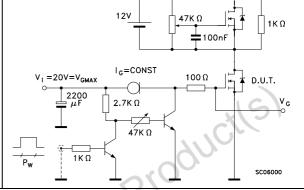
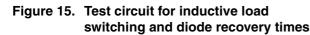
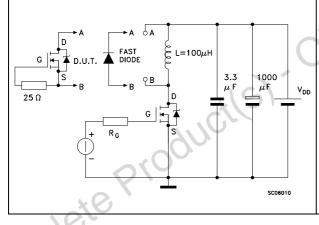
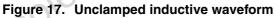


Figure 14. Gate charge test circuit







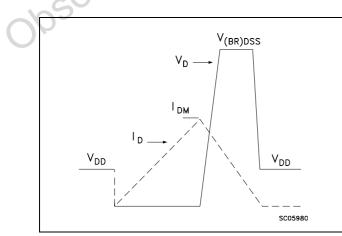


Figure 16. Unclamped inductive load test circuit

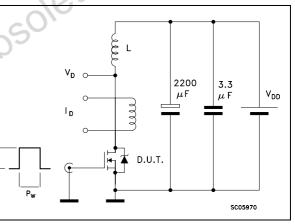
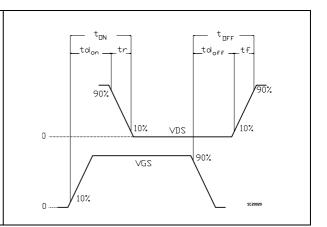


Figure 18. Switching time waveform



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4 Package mechanical data

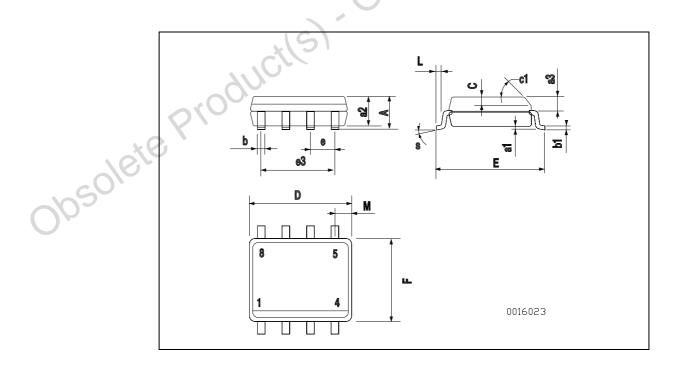
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Obsolete Product(s). Obsolete Product(s)



DIM.	mm.		inch			
DINI.	MIN.	ТҮР	MAX.	MIN.	TYP.	MAX.
Α			1.75			0.068
a1	0.1		0.25	0.003		0.009
a2			1.65			0.064
a3	0.65		0.85	0.025		0.033
b	0.35		0.48	0.013		0.018
b1	0.19		0.25	0.007		0.010
С	0.25		0.5	0.010		0.019
c1		•	45 (typ.)		
D	4.8		5.0	0.188		0.196
E	5.8		6.2	0.228		0.244
е		1.27		X	0.050	
e3		3.81		× 0, `	0.150	
F	3.8		4.0	0.14		0.157
L	0.4		1.27	0.015		0.050
М			0.6	-		0.023





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5 Revision history

Table 9. Document revision history

Date	Revision	Changes
19-Nov-2007	10	Document status promoted from preliminary data to datasheet

obsolete Product(s). Obsolete Product(s)

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